

Search Notes

Application/Control No.

10/760,651

Examiner

RAYMOND PHAN

Applicant(s)/Patent under
Reexamination

TIERNEY ET AL.

Art Unit

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SEARCHED

Class	Subclass	Date	Examiner
710	309-315, 105-107, 110-112	2/12/2008	RP
711	136-146	2/12/2008	RP

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
711	141,146	2/15/2008	RP

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR